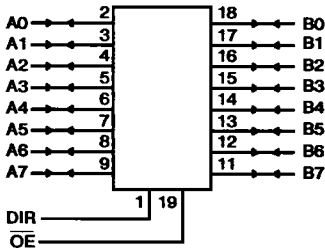


July 1990

## Octal-Bus Transceiver, 3-State, Non-Inverting



FUNCTIONAL DIAGRAM

**Type Features:**

- Buffered inputs
- Typical propagation delay:  
4.4ns @ VCC = 5V, TA = +25°C, CL = 50pF (FCT245AT)

**Family Features:**

- SCR-latchup-resistant BiCMOS process and circuit design
- FCTXXX Types - Speed of bipolar FAST\*/AS/S;
- FCTXXXAT Types - 30% faster than FAST/AS/S with significantly reduced power consumption
- 64/48-mA output sink current (commercial/extended industrial)
- Output voltage swing limited to 3.7V @ VCC = 5V
- Controlled output-edge rates
- Input/output isolation to VCC
- BiCMOS technology with low quiescent power

\* FAST is a registered trademark of Fairchild Semiconductor Corp.

The CD54/74FCT245 and CD54/74FCT245AT octal-bus transceivers use a small-geometry BiCMOS technology. The output stage is a combination of bipolar and CMOS transistors that limits the output-HIGH level to two diode drops below VCC. This resultant lowering of output swing (0V to 3.7V) reduces power bus ringing (a source of EMI) and minimizes VCC bounce and ground bounce and their effects during simultaneous output switching. The output configuration also enhances switching speed and is capable of sinking 48 to 64 milliamperes.

The CD54/74FCT245 and CD54/74FCT245AT are non-inverting, 3-state, bidirectional transceiver-buffers intended for two-way transmission from "A" bus to "B" bus or "B" bus to "A" bus. The logic level present on the Direction Input (DIR) determines the data direction. When the Output Enable input ( $\overline{OE}$ ) is HIGH, the outputs are in the high-impedance state.

The CD54/74FCT245 and CD54/74FCT245AT are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over two temperature ranges: Commercial (0°C to +70°C) and Extended Industrial (-55°C to +125°C).

The CD54FCT245 is also available in chip form (H suffix). These unpackaged devices are operable over the -55°C to +125°C temperature range.

**TRUTH TABLE**

CONTROL INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B Data to A Bus
L	H	A Data to B Bus
H	X	Isolation

H = High level, L = Low level, X = Irrelevant

To prevent excess currents in the High-Z (isolation) modes, all I/O terminals should be terminated with 10k $\Omega$  to 1M $\Omega$  resistors.

**MAXIMUM RATINGS, Absolute-Maximum Values:**

DC SUPPLY-VOLTAGE (VCC)	-0.5V to 6V
DC INPUT DIODE CURRENT, I <sub>IK</sub> (for V <sub>I</sub> < -0.5V)	-20mA
DC OUTPUT DIODE CURRENT, I <sub>OK</sub> (for V <sub>O</sub> < -0.5V)	-50mA
DC OUTPUT SINK CURRENT per Output Pin, I <sub>O</sub>	+70mA
DC OUTPUT SOURCE CURRENT per Output Pin, I <sub>O</sub>	-30mA
DC VCC CURRENT (I <sub>CC</sub> )	140mA
DC GROUND CURRENT (I <sub>GND</sub> )	528mA
<b>POWER DISSIPATION PER PACKAGE (PD):</b>	
For TA = -55°C to +100°C (PACKAGE TYPE E)	500mW
For TA = +100°C to +125°C (PACKAGE TYPE E)	Derate Linearly at 8mW/°C to 300mW
For TA = -55°C to +70°C (PACKAGE TYPE M)	400mW
For TA = +70°C to +125°C (PACKAGE TYPE M)	Derate Linearly at 8mW/°C to 70mW
<b>OPERATING-TEMPERATURE RANGE (TA):</b>	
PACKAGE TYPE E, M	-55°C to +125°C
<b>STORAGE TEMPERATURE (T<sub>stg</sub>)</b>	-65°C to +150°C
<b>LEAD TEMPERATURE (DURING SOLDERING):</b>	
At distance 1/16 in. ± 1/32 in. (1.59mm ± 0.79mm) from case for 10s maximum	+265°C
Unit inserted into PC board min. thickness 1/16 in. (1.59mm) with solder contacting lead tips only	+300°C

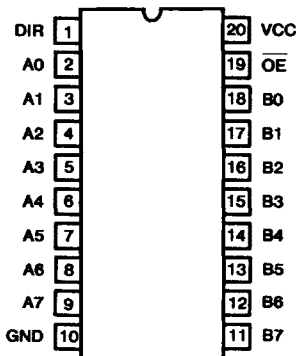
**RECOMMENDED OPERATING CONDITIONS:**

The following are normal operating ranges for these devices. For maximum reliability, devices should always be operated within these ranges.

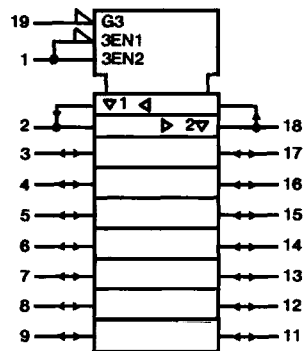
CHARACTERISTIC	LIMITS		UNITS
	MIN	MAX	
Supply-Voltage Range, VCC*: CD74 Series, TA = 0°C to 70°C	4.75	5.25	V
	CD54 Series, TA = -55°C to +125°C	4.5	5.5
DC Input Voltage, V <sub>I</sub>	0	VCC	V
DC Output Voltage, V <sub>O</sub>	0	≤ VCC	V
Operating Temperature, TA	-55	+125	°C
Input Rise and Fall Slew Rate, dt/dv	0	10	ns/V

\* Unless otherwise specified, all voltages are referenced to ground.

4  
TECHNICAL DATA



TERMINAL ASSIGNMENT



IEC LOGIC SYMBOL

**STATIC ELECTRICAL CHARACTERISTICS**

FCT Series: 74FCT Commercial Temperature Range, 0°C to +70°C; VCC max = 5.25V, VCC min = 4.75V

54FCT Extended Industrial Temperature Range, -55°C to +125°C; VCC max = 5.5V, VCC min = 4.5V

CHARACTERISTICS		TEST CONDITIONS			AMBIENT TEMPERATURE (TA)						UNITS
		VI (V)	IO (mA)	VCC (V)	+25°C		0°C to +70°C		-55°C to +125°C		
					MIN	MAX	MIN	MAX	MIN	MAX	
High-Level Input Voltage	VIH			4.5 to 5.5	2	-	2	-	2	-	V
Low-Level Input Voltage	VIL			4.5 to 5.5	-	0.8	-	0.8	-	0.8	V
High-Level Output Voltage	VOH	VIH or	-15	MIN	2.4	-	2.4	-	-	-	V
		VIL	-12	MIN	2.4	-	-	-	2.4	-	V
Low-Level Output Voltage	VOL	VIH or	64	MIN	-	0.55	-	0.55	-	-	V
		VIL	48	MIN	-	0.55	-	-	-	0.55	V
High-Level Input Current	I <sub>IH</sub>	VCC		MAX	-	0.1	-	1	-	1	μA
Low-Level Input Current	I <sub>IL</sub>	GND		MAX	-	-0.1	-	-1	-	-1	μA
3-State Leakage Current	IOZH	VCC		MAX	-	0.5	-	10	-	10	μA
	IOZL	GND		MAX	-	-0.5	-	-10	-	-10	μA
Short-Circuit Output Current *	IOS	VCC or GND VO = 0		MAX	-60	-	-60	-	-60	-	mA
Input Clamp Voltage	V <sub>IK</sub>	VCC or GND	-18	MIN	-	-1.2	-	-1.2	-	-1.2	V
Quiescent Supply Current, MSI	ICC	VCC or GND	0	MAX	-	8	-	80	-	500	μA
Additional Quiescent Supply Current per Input Pin TTL Inputs High, 1 Unit Load	ΔICC	3.4V †		MAX	-	1.6	-	1.6	-	2	mA

\* Not more than one output should be shorted at one time. Test duration should not exceed 100ms.

† Inputs that are not measured are at VCC or GND.

FCT Input Loading: All inputs are 1 unit load. Unit load is ΔICC limit specified in Static Characteristics Chart, e.g., 1.6mA max. @ +70°C.

**SWITCHING CHARACTERISTICS**  $t_r, t_f = 2.5\text{ns}$ ,  $C_L = 50\text{pF}$ ,  $R_L$  - See Figure 3

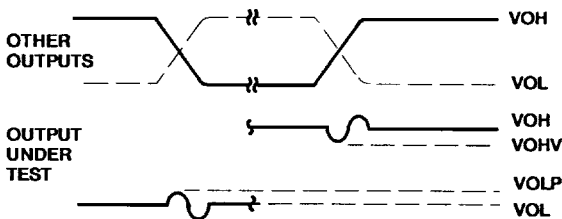
CHARACTERISTICS	SYMBOL	$V_{CC}$ (V)	CD54/74FCT245						CD54/74FCT245AT						UNITS
			AMBIENT TEMPERATURE ( $T_A$ )												
			+25°C		0°C to +70°C		-55°C to +125°C		+25°C		0°C to +70°C		-55°C to +125°C		
			TYP	MIN	MAX	MIN	MAX	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
Propagation Delays: Data to Outputs	$t_{PLH}$ $t_{PHL}$	5†	5	1.5	7	1.5	7.5	4.4	1.5	5.8	1.5	6.8	ns		
Output Disable to Output	$t_{PLZ}$ $t_{PHZ}$	5	6	1.5	7.5	1.5	10	5.4	1.5	6.5	1.5	7.8	ns		
Output Enable to Output	$t_{PZH}$ $t_{PZL}$	5	6	1.5	9.5	1.5	10	6	1.5	8	1.5	9.5	ns		
Power Dissipation Capacitance	$C_{PD}$ §	-	49 Typical										pF		
Min. (Valley) $V_{OHV}$ During Switching of Other Outputs (Output Under Test Not Switching)	$V_{OHV}$ See Figure 1	5	0.5 Typical @ +25°C										V		
Max. (Peak) $V_{OLP}$ During Switching of Other Outputs (Output Under Test Not Switching)	$V_{OLP}$ See Figure 1	5	1 Typical @ +25°C										V		
Input Capacitance	$C_I$	-	-	-	10	-	10	-	-	10	-	10	pF		
Input/Output Capacitance	$C_{I/O}$	-	-	-	15	-	15	-	-	15	-	15	pF		

†5V: min. is @ 5.5V  
max. is @ 4.5V

5V: min. is @ 5.25V for 0°C to +70°C  
max. is @ 4.75V for 0°C to +70°C  
typ. is @ 5V

§ $C_{PD}$ , measured per function, is used to determine the dynamic power consumption.  
 $P_D$  (per package) =  $V_{CC} I_{CC} + \Sigma (V_{CC}^2 f_i C_{PD} + V_O^2 f_o C_L + V_{CC} \Delta I_{CC} D)$  where:  
 $V_{CC}$  = supply voltage  
 $\Delta I_{CC}$  = flow through current x unit load  
 $C_L$  = output load capacitance  
 $D$  = duty cycle of Input high  
 $f_o$  = output frequency  
 $f_i$  = input frequency

**PARAMETER MEASUREMENT INFORMATION**



**NOTES:**

- $V_{OLP}$  is measured with respect to a ground reference near the output under test.  $V_{OHV}$  is measured with respect to  $V_{OH}$ .
- Input pulses have the following characteristics:  
 $PRR \leq 1\text{MHz}$ ,  $t_r = 2.5\text{ns}$ ,  $t_f = 2.5\text{ns}$ , skew 1ns.
- R.F. fixture with 700-MHz design rules required. IC should be soldered into test board and bypassed with 0.1µF capacitor. Scope and probes require 700-MHz bandwidth.

Figure 1 - Simultaneous switching transient waveforms.

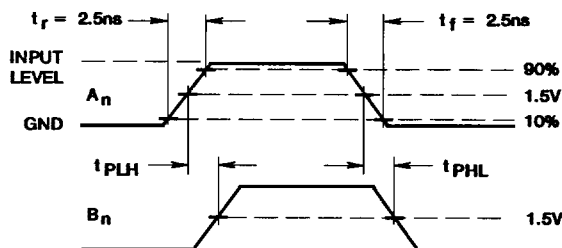
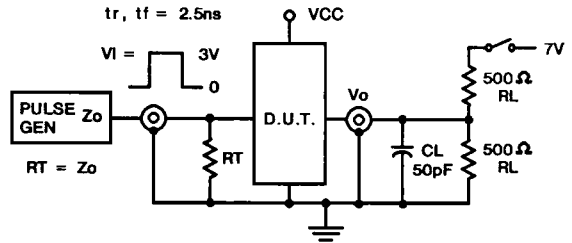
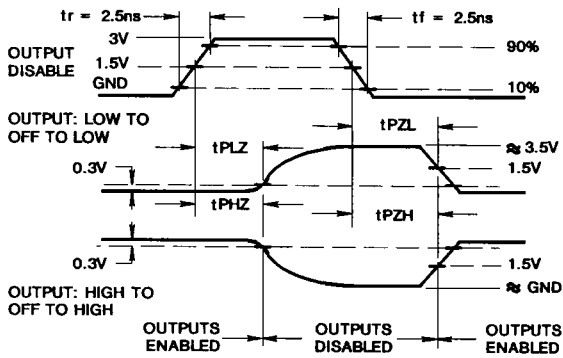


Figure 2 - Propagation delay times.



TEST	SWITCH POSITION
$t_{PLZ}, t_{PZL}, \text{OPEN DRAIN}$	CLOSED
$t_{PHZ}, t_{PZH}, t_{PLH}, t_{PHL}$	OPEN

Figure 3 - Three-state propagation delay times and test circuit.